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Application/Control No.	Applicant(s)/Patent under Reexamination
10/511,408	MAK, JOHN
Examiner	Art Unit
Ives Wu	1797

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SEARCHED				
Class	Subclass	Date	Examiner	
95	263,266,2 35	11/29/2007	ιwυ	
95	160,163	11/29/2007	ιwυ	
95	172,175	11/29/2007	ΙWU	
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH (INCLUDING SEAF	RCH STRATEGY)
	DATE	EXMR
inventor search - EAST	11/29/2007	IWU
text search - EAST	11/29/2007	-ιwυ